COMPLEMENTARY 60V ENHANCEMENT MODE MOSFET H-BRIDGE

SUMMARY

N-Channel $V_{(BR)DSS}$ = 60V; $R_{DS(ON)}$ = 0.300 Ω ; I_D = 1.8A P-Channel $V_{(BR)DSS}$ = -60V; $R_{DS(ON)}$ = 0.425 Ω ; I_D = -1.5A

DESCRIPTION

This new generation of trench MOSFETs from Zetex utilizes a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage, power management applications.

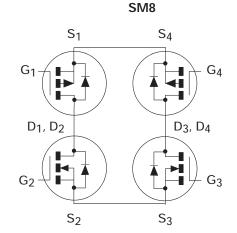


FEATURES

- · Low On Resistance
- · Fast switching speed
- · Low threshold
- Low gate drive
- SM8 package

APPLICATIONS

Motor drive



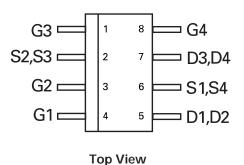
ORDERING INFORMATION

DEVICE	REEL SIZE	TAPE WIDTH	QUANTITY PER REEL
ZXMHC6A07T8TA	7''	12mm	1000 units
ZXMHC6A07T8TC	13''	12mm	4000 units

DEVICE MARKING

 ZXMH C6A07

PINOUT DIAGRAM



ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	N-Channel	P-Channel	UNIT
Drain-Source Voltage	V _{DSS}	60	-60	V
Gate-Source Voltage	V _{GS}	±20	±20	V
Continuous Drain Current@ V_{GS} =10V; T_A =25°C (b)(d) @ V_{GS} =10V; T_A =70°C (b)(d) @ V_{GS} =10V; T_A =25°C (a)(d)	I _D	1.8 1.4 1.6	-1.5 -1.2 -1.3	A A
Pulsed Drain Current ^(c)	I _{DM}	8.4	-7.2	А
Continuous Source Current (Body Diode) (b)	I _S	2.3	-2.1	А
Pulsed Source Current (Body Diode) (c)	I _{SM}	8.4	-7.2	А
Power Dissipation at T _A =25°C ^{(a)(d)} Linear Derating Factor	P _D	1.3 10.4		W mW/°C
Power Dissipation at T _A =25°C ^{(b)(d)} Linear Derating Factor	P _D	1	W mW/°C	
Operating and Storage Temperature Range	T _j :T _{stg}	-55 to	o +150	°C

THERMAL RESISTANCE

PARAMETER	SYMBOL	VALUE	UNIT
Junction to Ambient ^{(a)(d)}	$R_{\theta JA}$	94.5	°C/W
Junction to Ambient (b)(d)	$R_{\theta JA}$	73.3	°C/W

Notes:

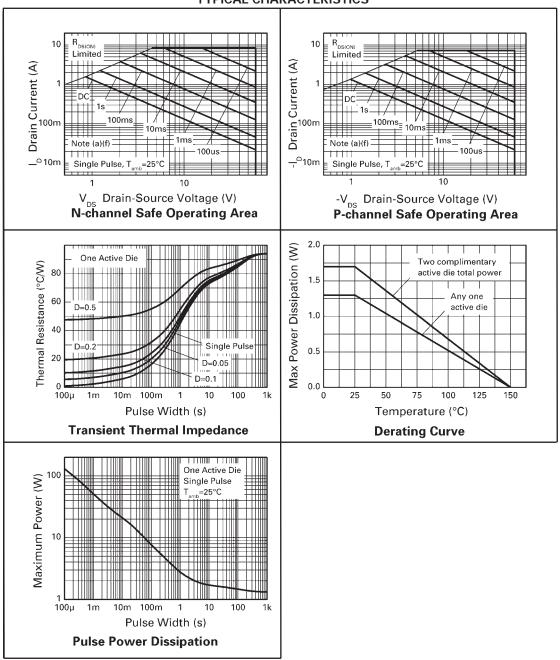
⁽a) For a device surface mounted on 50mm x 50mm x 1.6mm FR4 PCB with high coverage of single sided 2oz copper, in still air conditions with the heatsink split into two equal areas, one for each drain connection.

⁽b) For a device surface mounted on FR4 PCB measured 1.6mm at t \leq 10sec.

⁽c) Repetitive rating - 50mm x 50mm x 1.6mm FR4 PCB, D = 0.02, pulse width 300µs pulse width limited by maximum junction temperature. Refer to Transient Thermal Impedance graph.

⁽d) For device with one active die.

TYPICAL CHARACTERISTICS



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N-CHANNEL ELECTRICAL CHARACTERISTICS (at T_{amb} = 25°C unless otherwise stated)

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS		
STATIC		•						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	60			V	I _D =250μA, V _{GS} =0V		
Zero Gate Voltage Drain Current	I _{DSS}			1	μΑ	V _{DS} =60V, V _{GS} =0V		
Gate-Body Leakage	I _{GSS}			100	nA	V _{GS} =±20V, V _{DS} =0V		
Gate-Source Threshold Voltage	V _{GS(th)}	1		3.0	V	I _D =250μA, V _{DS} = V _{GS}		
Static Drain-Source On-State Resistance (1)	R _{DS(on)}			0.300 0.450	Ω Ω	V _{GS} =10V, I _D =1.8A V _{GS} =4.5V, I _D =1.3A		
Forward Transconductance (1)(3)	9 _{fs}		2.3		S	V _{DS} =15V,I _D =1.8A		
DYNAMIC (3)		1						
Input Capacitance	C _{iss}		166		pF	V 40V V 0V		
Output Capacitance	C _{oss}		19.5		pF	V _{DS} =40V, V _{GS} =0V, f=1MHz		
Reverse Transfer Capacitance	C _{rss}		8.7		pF			
SWITCHING (2) (3)								
Turn-On Delay Time	t _{d(on)}		1.8		ns			
Rise Time	t _r		1.4		ns	V _{DD} =30V, I _D =1.8A		
Turn-Off Delay Time	t _{d(off)}		4.9		ns	R _G ≅6.0Ω, V _{GS} =10V		
Fall Time	t _f		2.0		ns			
Gate Charge	Qg		1.65		nC	V _{DS} =30V,V _{GS} =5V, I _D =1.8A		
Total Gate Charge	Qg		3.2		nC	V 00VV 40V		
Gate-Source Charge	Q _{gs}		0.67		nC	$V_{DS} = 30V, V_{GS} = 10V, I_{D} = 1.8A$		
Gate-Drain Charge	Q _{gd}		0.82		nC			
SOURCE-DRAIN DIODE								
Diode Forward Voltage ⁽¹⁾	V _{SD}		0.85	0.95	V	T _J =25°C, I _S =0.45A, V _{GS} =0V		
Reverse Recovery Time ⁽³⁾	t _{rr}		20.5		ns	T _J =25°C, I _F =1.8A,		
Reverse Recovery Charge ⁽³⁾	Q _{rr}		21.3		nC	di/dt= 100A/µs		

NOTES

⁽¹⁾ Measured under pulsed conditions. Width ${\leq}300\mu s.$ Duty cycle ${\leq}~2\%$.

⁽²⁾ Switching characteristics are independent of operating junction temperature.

⁽³⁾ For design aid only, not subject to production testing.

P-CHANNEL ELECTRICAL CHARACTERISTICS (at T_{amb} = 25°C unless otherwise stated)

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS	
STATIC							
Drain-Source Breakdown Voltage	V _{(BR)DSS}	-60			V	I _D =-250μA, V _{GS} =0V	
Zero Gate Voltage Drain Current	I _{DSS}			-1	μΑ	V _{DS} =-60V, V _{GS} =0V	
Gate-Body Leakage	I _{GSS}			100	nA	V _{GS} =±20V, V _{DS} =0V	
Gate-Source Threshold Voltage	V _{GS(th)}	-1.0			V	I _D =-250μA, V _{DS} = V _{GS}	
Static Drain-Source On-State Resistance (1)	R _{DS(on)}			0.425 0.630	Ω Ω	V _{GS} =-10V, I _D =-0.9A V _{GS} =-4.5V, I _D =-0.8A	
Forward Transconductance (1)(3)	g _{fs}		1.8		S	V _{DS} =-15V,I _D =-0.9A	
DYNAMIC (3)				•			
Input Capacitance	C _{iss}		233		pF		
Output Capacitance	C _{oss}		17.4		pF	V _{DS} =-30 V, V _{GS} =0V, f=1MHz	
Reverse Transfer Capacitance	C _{rss}		9.6		pF		
SWITCHING ^{(2) (3)}			•		•		
Turn-On Delay Time	t _{d(on)}		1.6		ns		
Rise Time	t _r		2.3		ns	V _{DD} =-30V, I _D =-1A	
Turn-Off Delay Time	t _{d(off)}		13		ns	$R_{G\cong_{6.0}}\Omega$, $V_{GS}=-10V$	
Fall Time	t _f		5.8		ns		
Gate Charge	Qg		2.4		nC	V _{DS} =-30V,V _{GS} =-5V, I _D =-0.9A	
Total Gate Charge	Qg		5.1		nC		
Gate-Source Charge	Q _{gs}		0.7		nC	V _{DS} =-30V,V _{GS} =-10V, I _D =-0.9A	
Gate-Drain Charge	Q _{gd}		0.7		nC		
SOURCE-DRAIN DIODE	,	•	•		•		
Diode Forward Voltage ⁽¹⁾	V _{SD}		-0.85	-0.95	V	T _J =25°C, I _S =-0.8A, V _{GS} =0V	
Reverse Recovery Time (3)	t _{rr}		22.6		ns	T _J =25°C, I _F =-0.9A,	
Reverse Recovery Charge ⁽³⁾	Q _{rr}	23.:			nC	di/dt= 100A/µs	

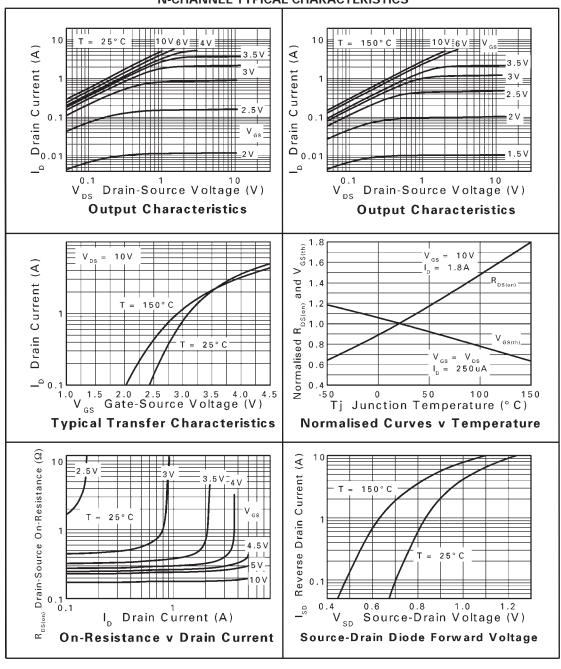
NOTES

⁽¹⁾ Measured under pulsed conditions. Width ${\leq}300\mu s.$ Duty cycle ${\leq}~2\%$.

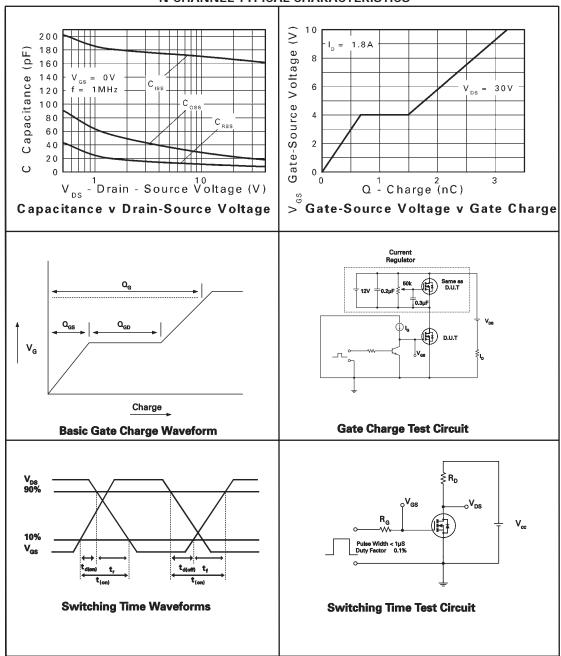
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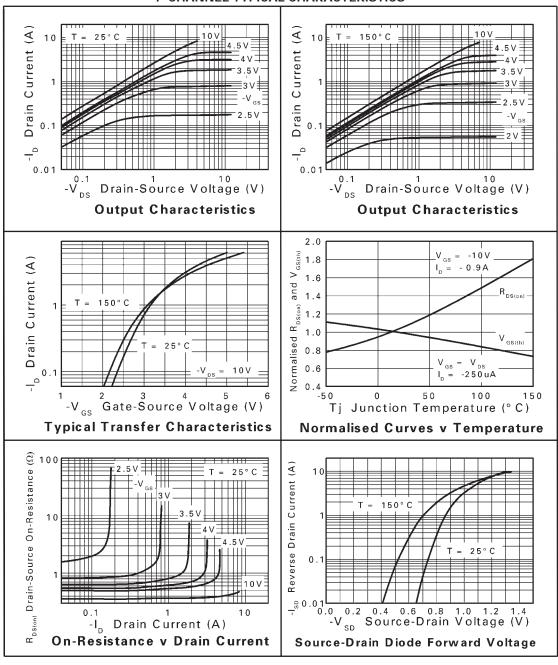
N-CHANNEL TYPICAL CHARACTERISTICS



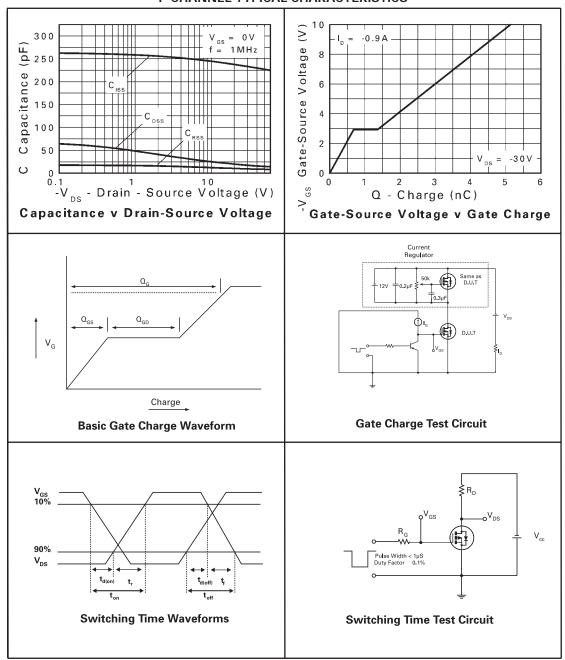
N-CHANNEL TYPICAL CHARACTERISTICS



P-CHANNEL TYPICAL CHARACTERISTICS

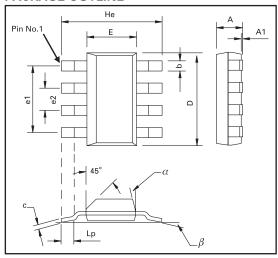


P-CHANNEL TYPICAL CHARACTERISTICS



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PACKAGE OUTLINE



Controlling dimensions are in millimeters. Approximate conversions are given in inches

PACKAGE DIMENSIONS

	М	Millimeters		Inches				illimete	ers		Inches	3	
DIM	Min	Max	Тур.	Min	Max	Тур.	DIM	Min	Max	Тур.	Min	Max	Тур.
Α	-	1.7	-	-	0.067	-	e1	-	-	4.59	-	-	0.1807
A1	0.02	0.1	-	0.008	0.004	-	e2	-	-	1.53	-	-	0.0602
b	-	-	0.7	-	-	0.0275	He	6.7	7.3	-	0.264	0.287	-
С	0.24	0.32	-	0.009	0.013	-	Lp	0.9	-	-	0.035	-	-
D	6.3	6.7	-	0.248	0.264	-	α	-	15°	-	-	15°	-
Е	3.3	3.7	-	0.130	0.145	-	β	-	-	10°	-	-	10°

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